



## Product Change Notification / LIAL-07RPOQ740

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**Date:**

13-Dec-2022

**Product Category:**

Ethernet PHYs

**PCN Type:**

Manufacturing Change

**Notification Subject:**

CCB 5135 Final Notice: Qualification of a new lead frame with more Ag area on DAP surface prep for selected KSZ8081 and KSZ8091 device families available in 32L VQFN (5x5x0.9mm) package assembled at MTAI assembly site.

**Affected CPNs:**

[LIAL-07RPOQ740\\_Affected\\_CPN\\_12132022.pdf](#)

[LIAL-07RPOQ740\\_Affected\\_CPN\\_12132022.csv](#)

**Notification Text:**

**PCN Status:**Final Notification

**PCN Type:**Manufacturing Change

**Microchip Parts Affected:**Please open one of the files found in the Affected CPNs section.

Note: For your convenience Microchip includes identical files in two formats (.pdf and .xls)

**Description of Change:**Qualification of a new lead frame with more Ag area on DAP surface prep for selected KSZ8081 and KSZ8091 device families available in 32L VQFN (5x5x0.9mm) package assembled at MTAI assembly site.

**Pre and Post Change Summary:**

	Pre Change	Post Change
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Affected Catalog Part Numbers (CPN)

KSZ8091RNBCA  
KSZ8081MNXCA  
KSZ8091MNXCA  
KSZ8081MNXIA  
KSZ8081RNBCA-TR  
KSZ8091RNBCA-TR  
KSZ8081MNXCA-TR  
KSZ8091MNXCA-TR  
KSZ8081RNBIA-TR  
KSZ8091RNBIA-TR  
KSZ8081MNXIA-TR  
KSZ8091MNXIA-TR  
SPNZ801174

**CCB#: 5135**  
**Pre and Post Change Summary**  
**PCN #: LIAL-07RPOQ740**



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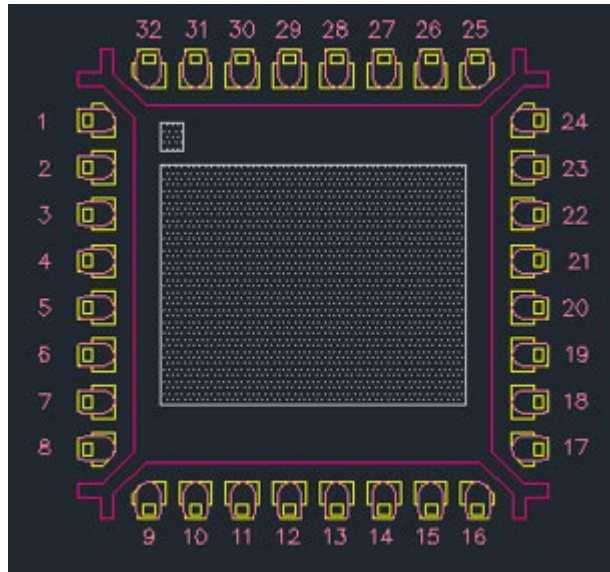
A Leading Provider of Smart, Connected and Secure Embedded Control Solutions



SMART | CONNECTED | SECURE

# Lead Frame Comparison

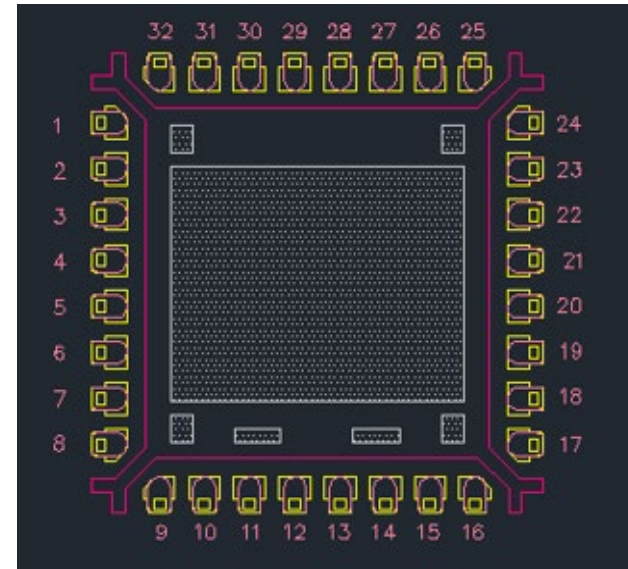
## Pre Change



Lead frame DAP surface prep

Ag selective plating

## Post Change



Lead frame DAP surface prep

Ag selective plating  
(Add more Ag area)



**MICROCHIP**

**QUALIFICATION REPORT SUMMARY**  
RELIABILITY LABORATORY

**PCN# LIAL-07RPOQ740**

**Date**  
**November 25, 2022**

**Qualification of a new lead frame with more Ag area on DAP surface prep for selected KSZ8081 and KSZ8091 device families available in 32L VQFN (5x5x0.9mm) package assembled at MTAI assembly site.**



## MICROCHIP PACKAGE QUALIFICATION REPORT

**Purpose** Qualification of a new lead frame with more Ag area on DAP surface prep for selected KSZ8081 and KSZ8091 device families available in 32L VQFN (5x5x0.9mm) package assembled at MTAI assembly site.

**CN** E000107074  
**QUAL ID** R2200733 Rev A  
**MP CODE** XKAA19PFAVA2  
**Part No.** KSZ8051MNLV-VAO  
**Bonding No.** BD-000677 Rev.02  
**CCB** 5135

### Package

**Type** 32L VQFN  
**Package size** 5 x 5 x 0.9 mm

### Lead Frame

**Paddle size** 150 x 150 mils  
**Material** A194  
**Surface** Ag selective plating (Add more Ag area)  
**Process** Etched  
**Lead Lock** Yes  
**Part Number** 10103214

### Material

**Epoxy** 3280  
**Wire** Au/2N  
**Mold Compound** G700LTD  
**Plating Composition** Matte Sn





## MICROCHIP PACKAGE QUALIFICATION REPORT

### Manufacturing Information:

Assembly Lot No.	Wafer Lot No.	Date Code
MTAI230601567.000	DU02922523132.430	2219PAK
MTAI230601935.000	DU02922523132.430	2219Q83
MTAI230601936.000	DU02922523132.430	2219Q8D

### Result

Pass  Fail  \_\_\_\_\_

32L VQFN (5x5x0.9 mm) assembled by MTAI pass reliability test per QCI-39000.  
This package was qualified the Moisture/Reflow Sensitivity Classification Level 2 at 260°C  
reflow temperature per IPC/JEDEC J-STD-020E standard.

# PACKAGE QUALIFICATION REPORT

Test Number (Reference)	Test Condition	Standard/ Method	Qty. (Acc.)	Def/SS	Result	Remarks
<b>Precondition Prior Perform Reliability Tests (At MSL Level 2)</b>	<b>Electrical Test:</b> +25°C, 105°C and -43°C System: Chroma / SMB600	JESD22-A113	693(0)	0/693		Good Devices
	Bake 150°C, 24 hrs System: CHINEE	JIP/ IPC/JEDEC J-STD-020E		0/693		
	85°C/60%RH Moisture Soak 168 hrs. System: TABAI ESPEC Model PR-3SPH 3x Convection-Reflow 265°C max			0/693		
	System: Vitronics Soltec MR1243			0/693		
<b>Electrical Test:</b> +25°C and 105°C System: Chroma / SMB600		693(0)	0/693	Pass		
<b>Temp Cycle</b>	<b>Stress Condition:</b> -55°C to +125°C, 1000 Cycles System: TABAI ESPEC TSA-70H	JESD22-A104		0/231		Parts had been pre-conditioned at 260°C
	<b>Electrical Test:</b> +25°C and 105°C System: Chroma		231(0)	0/231	Pass	77 units / lot
	<b>Bond Strength:</b> Wire Pull (>2.50 grams) Bond Shear (>15.00 grams)		15(0) 15(0)	0/15 0/15	Pass Pass	
<b>UNBIASED-HAST</b>	<b>Stress Condition:</b> +130°C/85%RH, 96 hrs. System: HAST 6000X	JESD22-A118		0/231		Parts had been pre-conditioned at 260°C
	<b>Electrical Test:</b> +25°C System: SMB600		231(0)	0/231	Pass	77 units / lot
<b>HAST</b>	<b>Stress Condition:</b> +130°C/85%RH, 96 hrs. <b>Bias Volt:</b> 3.3 Volts System: HAST 6000X	JESD22-A110		0/231		Parts had been pre-conditioned at 260°C
	<b>Electrical Test:</b> +25°C and 105°C System: Chroma / SMB600		231(0)	0/231	Pass	77 units / lot

# PACKAGE QUALIFICATION REPORT

Test Number (Reference)	Test Condition	Standard/ Method	Qty. (Acc.)	Def/SS.	Result	Remarks
<p style="text-align: center;"><b>High Temperature Storage Life</b></p>	<p><b>Stress Condition:</b> Bake 150°C, 500 hrs. System: SHEL LAB</p>	<p>JESD22- A103</p>		0/45		
	<p><b>Electrical Test:</b> +25°C and 105°C System: Chroma / SMB600</p>		45(0)	0/45	Pass	
<p><b>Bond Strength Data Assembly</b></p>	Wire Pull (>2.50 grams)	Mil. Std. 883-2011	30(0) Wires	0/30	Pass	
	Bond Shear (>15.00 grams)	CDF-AEC- Q100-001	30(0) bonds	0/30	Pass	